

Application No.	Applicant(s)	
10/666,968	HADY ET AL.	
Examiner	Art Unit	
Folix F Sugrez	2857	

ORIGINAL CLASS SUBCLASS CLASS 702 188 702 INTERNATIONAL CLASSIFICATION			CROSS REFERENCE(S)	
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INTERNATIONAL CLASSIFICATION	4	SUBCLA	SS (ONE SUBCLASS P	ER BLOCK)	
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Felix Suarez 09/15/2004	/	Many Hoff MARCS ABOFF		Total Claims Allo	owed: 16
(Assistant Examiner) (Date)		MARC S. HOFF	IINICO		
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I Nand 9/A2 Hel	SUPERI	HNOLOGY CENTER 28	100 4/20/04	Print Claim(s)	Print Fig.
(Denai Instruments Exampler) (Care)	⟨Phi	ISORY PATENT CO INOLOGY CENTER 28 Mary Examiner)	(Date)	1	1
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Claims renumbered in the same orde	r ac procon	tod by applicant	☐ CPA	☐ T.D.	☐ R.1.47
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2 14 32	62	92	122	152	182
3 15 33	63	93	123	153	183
4 16 34	64	94	124	154	184
5 35	65	95	125	155	185
6 36	66	96	126	156	186
7 37 8 38	67	97	127	157	187
9 39	68 69	98	128	158 159	188
10 40	70	100	130	160	190
11 41	71	101	131	161	191
12 42	72	102	132	162	192
13 43	73	103	133	163	193
14 44	74	104	134	164	194
15 45	75	105	135	165	195
16 46	76	106	136	166	196
17 47	77	107	137	167	197
18 48	78	108	138	168	198
1 19 49	79	109	139	169	199
2 20 50	80 81	110	140	170	200
4 22 52	82	111	141	171	201
5 23 53	83	113	143	173	202
6 24 54	84	114	144	174	203
7 25 55	85	115	145	175	205
8 26 56	86	116	146	176	206
9 27 57	87	117	147	177	207
10 28 58	88	118	148	178	208
11 29 59	89	119	149	179	209
12 30 60	90	120	150	180	210